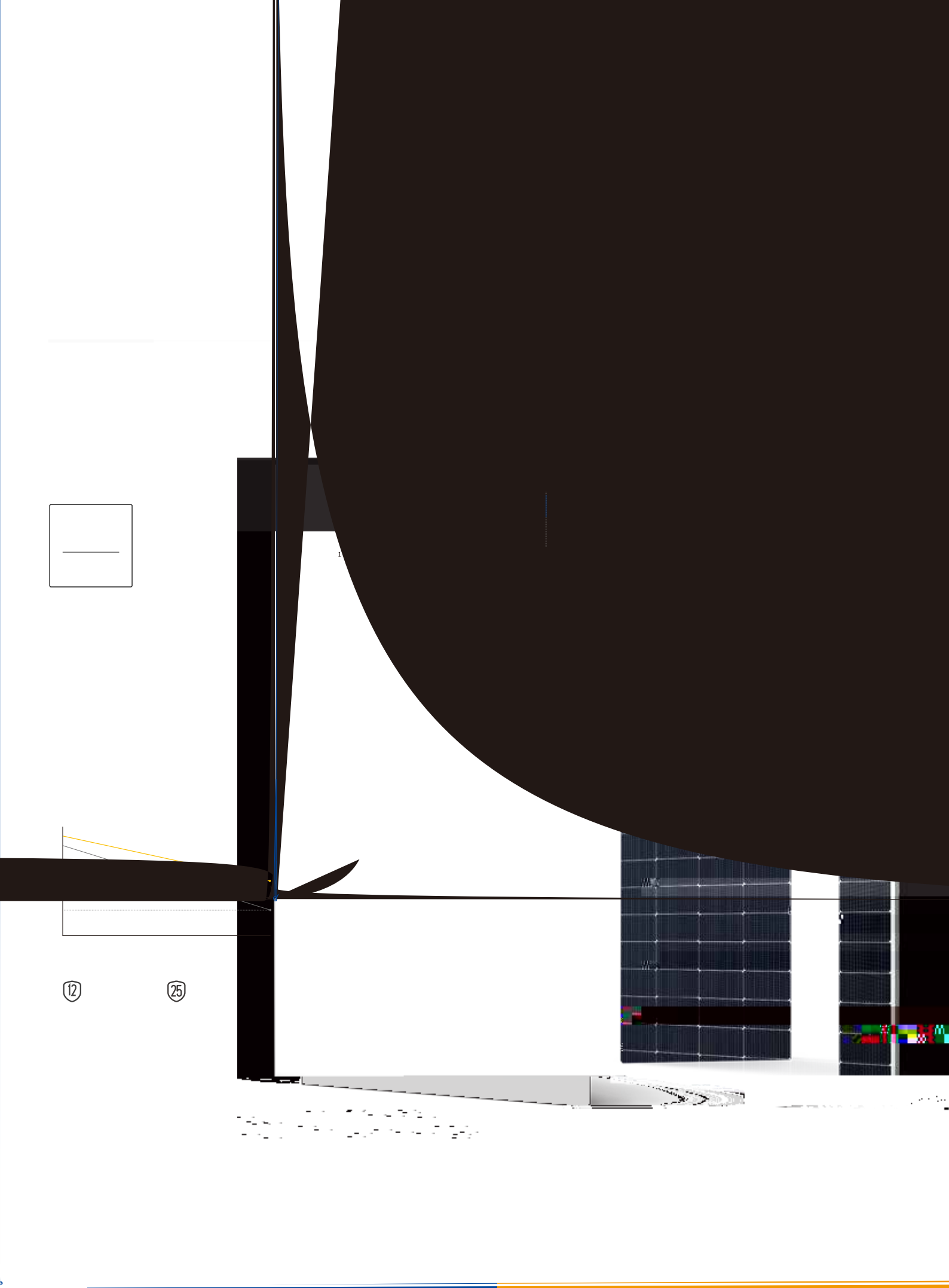






Measurement tolerance at SI